FCC EMC TEST REPORT

ISSUED BY Shenzhen BALUN Technology Co., Ltd.

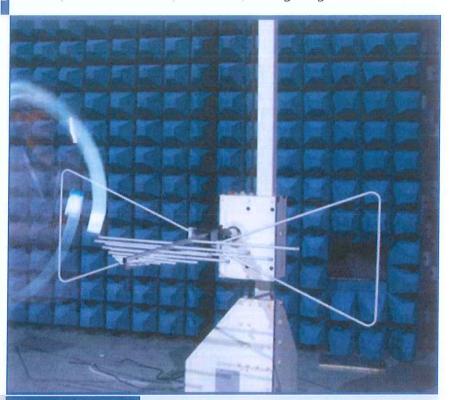


FOR

Led Marker

ISSUED TO
Guangdong Virtual Reality Technology Co,. Ltd

Shenzhen Flour Limited, South Gate 3rd Floor, 9106 Beihuan Avenue, Nanshan District, Shenzhen, Guangdong



Tested by:

Xia Long

Xia Long

(Engineer)

Jul. 11 2017

Approved by:

Wei Yanquan

(Chief Engineer)

Date

Date

Date

Date

Report No.: EUT Name:

EUT Name: Model Name:

Brand Name: Test Standard:

est Standard: FCC ID:

Test Conclusion:

Test Conclusion: Test Date: Date of Issue: BL-SZ1750414-402

Led Marker

XCV01-LM, IH D300

Ximmerse

47 CFR Part 15 Subpart B

2ALLR-XCV01-LM

Pass

Jun. 09, 2017 ~ Jun. 10, 2017

Jul. 11, 2017

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Revision History

VersionIssue DateRevisions ContentRev. 01Jul. 04, 2017Initial Issue

Rev. 02 Jul. 11, 2017 Increase the brand name

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1 GENERAL INFORMATION

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.
Addross	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi
Address	Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.
Addross	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi
Address	Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
	The laboratory has been listed by Industry Canada to perform
	electromagnetic emission measurements. The recognition numbers
	of test site are 11524A-1.
A	The laboratory has been listed by US Federal Communications
Accreditation	Commission to perform electromagnetic emission measurements.
Certificate	The recognition numbers of test site are 832625.
	The laboratory is a testing organization accredited by China National
	Accreditation Service for Conformity Assessment (CNAS) according
	to ISO/IEC 17025. The accreditation certificate number is L6791.
	All measurement facilities used to collect the measurement data are
Description	located at Block B, FL 1, Baisha Science and Technology Park, Shahe
Description	Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R.
	China 518055

1.3 Laboratory Condition

Ambient Temperature	20°C~25°C
Ambient Relative Humidity	45% - 55%
Ambient Pressure	100 kPa - 102 kPa

1.4 Announce

- (1) The test report reference to the report template version v6.5.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (5) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (6) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.



2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant Guangdong Virtual Reality Technology C		Guangdong Virtual Reality Technology Co,. Ltd
٨٨	Idroop	Shenzhen Flour Limited, South Gate 3rd Floor, 9106 Beihuan
Au	ldress	Avenue, Nanshan District, Shenzhen, Guangdong

2.2 Manufacturer Information

Manufacturer	Guangdong Virtual Reality Technology Co,. Ltd	
Address	Shenzhen Flour Limited, South Gate 3rd Floor, 9106 Beihuan	
Address	Avenue, Nanshan District, Shenzhen, Guangdong	

2.3 Factory Information

Factory	Shenzhen Kaifa Technology Co,. Ltd
Address	Caitian Road 7006, Futian district, Shenzhen

2.4 General Description for Equipment under Test (EUT)

EUT Name	Led Marker	
Model Name Under Test	XCV01-LM	
Series Model Name	XCV01-LM, IH D300	
Description of Model	Their electrical circuit design, layout, components used and internal	
name differentiation	wiring are identical, Only the outer decoration is different.	
Hardware Version	В	
Software Version	V2.0	
Dimensions (Approx.)	N/A	
Weight (Approx.)	N/A	
Network and Wireless connectivity	2.4G ISM Band(GFSK modulation)	

2.5 Ancillary Equipment

	Ancillary Equipment 1	Motion Sensor	
		Model No.	XCV01-SC
Ī	Ancillary Equipment 2	Motion Controller	
		Model No.	XCV01-CB

2.6 Technical Information

Note: Not applicable.



3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title	
1	FCC 47 CFR Part 15	Unintentional Radiators	
ı	Subpart B (10-1-16 Edition)	Offiliteritional Radiators	
	ANSI C63.4-2014	American National Standard for Methods of	
		Measurement of Radio-Noise Emissions from Low-	
2		Voltage Electrical and Electronic Equipment in the	
		Range of 9 kHz to 40 GHz	

3.2 Verdict

No. Description		FCC Rule	Test Verdict	Result
1	Radiated Emission	15.109	Pass	Annex A .1
2	Conducted Emission, AC Ports	15.107	N/A	Annex A .2

Note: The EUT only powered by Phone, so the Conducted Emission test is not applicable.

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9 kHz-30 MHz)	3.23 dB
Radiated emissions (30 MHz-1 GHz)	4.30 dB
Radiated emissions (1 GHz-18 GHz)	4.81 dB
Radiated emissions (18 GHz-40 GHz)	5.71 dB



4 GENERAL TEST CONFIGURATIONS

4.1 Test Environments

Environment	Selected Values During Tests				
Parameter	Temperature	Voltage	Relative Humidity	Ambient Pressure	
Normal Temperature, Normal Voltage (NTNV)	23°C~26°C	DC 5 V from Phone	50%-55%	100 to 102 kPa	

4.2 Test Equipment List

	Radiated Emission Test For Frequency Below 1 GHz								
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use			
EMI Receiver	ROHDE&SCHWA RZ	ESRP	101036	2016.07.05	2017.07.04	\boxtimes			
Test Antenna- Bi-Log	SCHWARZBECK	VULB 9163	9163-977	2016.07.19	2018.07.18	\boxtimes			
Test Antenna- Horn	SCHWARZBECK	BBHA 9120D	9120D-1600	2016.07.12	2018.07.11				
Anechoic Chamber	EMC Electronic Co., Ltd	20.10*11.60 *7.35m	N/A	2016.08.09	2018.08.08	\boxtimes			

	Radiated Emission Test For Frequency Above 1 GHz								
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use			
EMI Receiver	KEYSIGHT	N9038A	MY53220118	2016.09.09	2017.09.08	\boxtimes			
Test Antenna-	SCHWARZBECK	VULB 9163	9163-624	2015.07.22	2017.07.21				
Bi-Log	SCHWARZBLOK	VOLD 9103	9103-024	2013.07.22	2017.07.21				
Test Antenna-	SCHWARZBECK	BBHA	9120D-1148	2015.07.22	2017.07.21	\boxtimes			
Horn	SCHWARZBECK	9120D	91200-1146	2015.07.22	2017.07.21				
Anechoic	RAINFORD	9m*6m*6m	N/A	2017.02.21	2019.02.20	\boxtimes			
Chamber	RAINFORD	וווס וווס ווופ	IN/A	2017.02.21	2019.02.20				

	Conducted Emission Test								
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use			
EMI Receiver	ROHDE&SCHWA RZ	ESRP	101036	2016.07.05	2017.07.04				
LISN	SCHWARZBECK	NSLK 8127	8127-687	2016.07.05	2017.07.04				
LISN	SCHWARZBECK	NNLK 8129	8129-462	2016.09.14	2017.09.13				
AMN	SCHWARZBECK	NNBM8124	8124-509	2016.07.05	2017.07.04				
AMN	SCHWARZBECK	NNBM8124	8124-510	2016.07.05	2017.07.04				
ISN	TESEQ	ISN T800	34449	2016.07.05	2017.07.04				
Shielded Enclosure	ChangNing	CN-130701	130703	N/A	N/A				



4.3 Test Enclosure list

Description	Manufacturer	Model	Serial No.	Length	Description	Use
PC	Dell	015K3N	N/A	N/A	Special Handled	
Laptop	Apple	A1465	N/A	N/A	N/A	\boxtimes
Printer	HP	DESKJET 1000	N/A	N/A	N/A	
Keyboard	Logitech	Y-BP62a	N/A	N/A	N/A	
Mouse	Logitech	M100	N/A	N/A	N/A	
USB disk	Kingston	N/A N/A N/A		N/A	N/A	
TF Card	Kingston	N/A	N/A	N/A	N/A	
VGA Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
HDMI Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
DVI Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
Coaxial video cable	N/A	N/A	N/A	2.0 m	Shielded with core	
iPhone	Apple	A1586	N/A	N/A	N/A	
Phone	Huawei	MATE 8	N/A	N/A	N/A	\boxtimes
Bluetooth Earphone	SAMSUNG	Gear Circle	N/A	N/A	N/A	
GPS/GLONAS S Vector signal generator	R&S	N5172B EXG	N/A	N/A	N/A	
WIFI Router	TP-LINK	TL-WDR7500	N/A	N/A	N/A	
Earphone	N/A	OPPO	N/A	1.1 m	N/A	
Car Battery	Camel	55530	N/A	N/A	12 V/55 Ah	
Artificial load	N/A	N/A	N/A	N/A	2.5 Ω/100 W	
Artificial load	N/A	N/A	N/A	N/A	5 Ω/100 W	
Electronic Load	ITECH	IT8511	N/A	N/A	N/A	
USB Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
DC Power Supply	ITECH	IT6863A	60001401068 7210006	N/A	N/A	
LCD Monitor	SAMSUNG	UA32C4000P	N/A	N/A	N/A	
LCD Monitor	Dell	U241HB	N/A	N/A	N/A	
OTG Cable	N/A	N/A	N/A	0.15 m	Shielded with core	\boxtimes



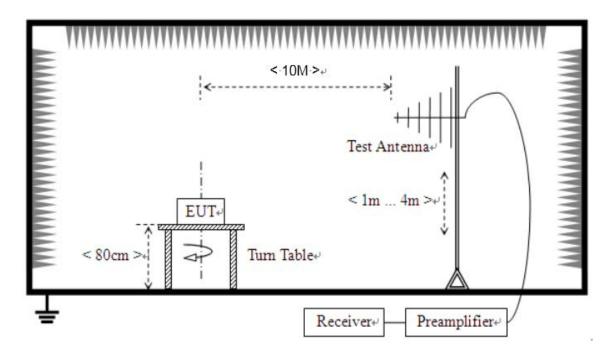
4.4 Test Configurations

Test Configurations (TC) No.	Description
TC01	<u>The Working Test Mode</u> EUT + Motion Sensor + Motion Controller + Laptop + Phone + OTG Cable



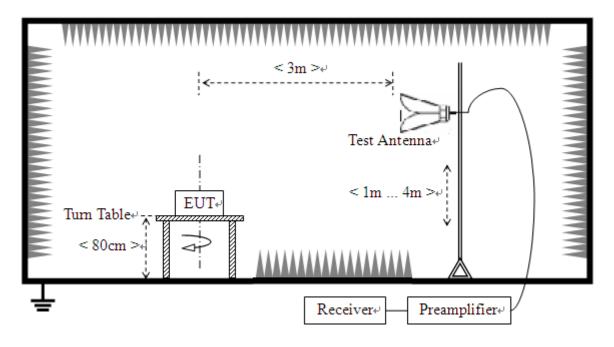
4.5 Test Setups

Test Setup 1



(For Radiated Emission Test (30 MHz-1 GHz))

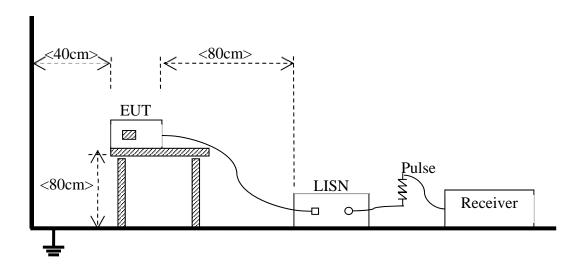
Test Setup 2



(For Radiated Emission Test (above 1 GHz))



Test Setup 3



(For Conducted Emission, AC Ports Test)



4.6 Test Conditions

Test Case	Test Conditions		
	Test Env.	NTNV	
Radiated Emission	Test Setup	Test Setup 1&2	
	Test Configuration	TC01 Note	

Note: Based on client request, all normal using modes of the normal function were tested but only the worst test data of the worst mode is reported by this report. The Working Test Mode is the worst mode in this report.



5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range	Class B	(at 10 m)	Class A (at 10 m)		
	Field Strength Field Strength		Field Strength	Field Strength	
(MHz)	(μV/m)	(dBµV/m)	(μV/m)	(dBµV/m)	
30 - 88	100	30	90	39	
88 - 216	150	33.5	150	43.5	
216 - 960	200	36	210	46.4	
Above 960	500	44	300	49.5	

NOTE:

- 1) Field Strength ($dB\mu V/m$) = 20*log [Field Strength ($\mu V/m$)].
- 2) In the emission tables above, the tighter limit applies at the band edges.

5.1.1.2 Test Setup

Refer to 4.5 section (test setup 1 to test setup 2) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Spurious Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

5.1.1.4 Test Result

Please refer to ANNEX A.1.



5.1.2 Conducted Emission

5.1.2.1 Test Limit

	Cla	ass A
Frequency range (MHz)	uency range (MHz) Quasi-peak	
	(dBµV)	(dBµV)
0.15 - 0.50	79	66
0.50 - 30	73	60

	Cla	ass B
Frequency range (MHz)	Quasi-peak	Average
	(dBµV)	(dBµV)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.5 section test (test setup 3) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides $50 \Omega/50 \mu H$ of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

5.1.2.4 Test Result

Please refer to ANNEX A.2.



ANNEX A TEST RESULTS

A.1 Radiated Emission

Note 1: The symbol of "--" in the table which means not application.

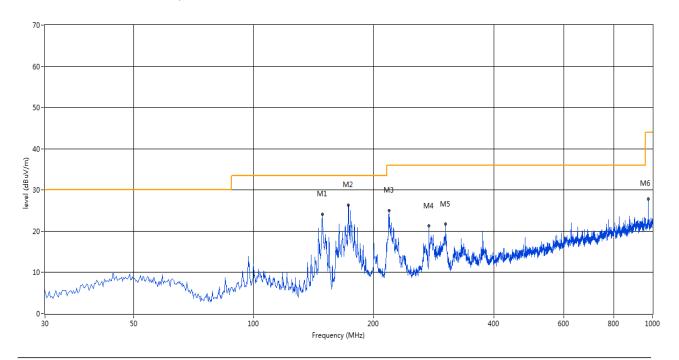
Note 2: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

Note 3: The marked spikes near 2400 MHz with circle should be ignored because they are 2.4G ISM Band(GFSK modulation).

Test Data and Plots

The Working Test Mode

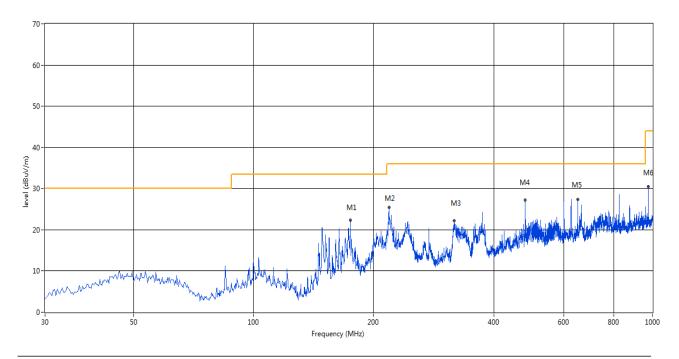
A.1.1 Test Antenna Vertical, 30 MHz – 1 GHz



No.	Frequency	Results	Factor (dB)	Limit	Margin	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	148.553	24.13	-18.76	33.5	9.37	Peak	288.00	100	Vertical	Pass
2	172.797	26.37	-17.46	33.5	7.13	Peak	127.00	100	Vertical	Pass
3	218.375	24.99	-14.90	36.0	11.01	Peak	9.00	100	Vertical	Pass
4	274.864	21.24	-13.02	36.0	14.76	Peak	258.00	100	Vertical	Pass
5	302.987	21.69	-12.38	36.0	14.31	Peak	0.00	200	Vertical	Pass
6	974.786	27.76	-0.48	44.0	16.24	Peak	360.00	300	Vertical	Pass



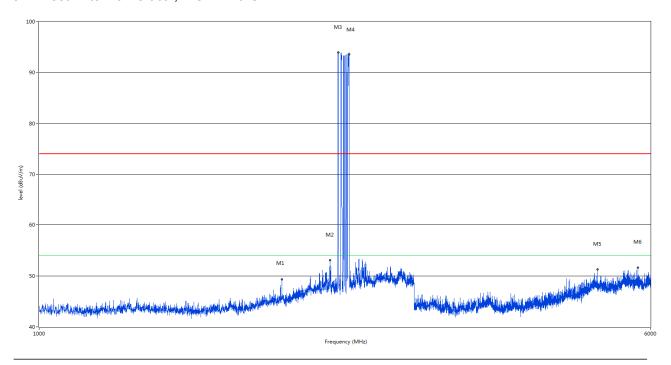
A.1.2 Test Antenna Horizontal, 30 MHz – 1 GHz



No.	Frequency	Results	Factor (dB)	Limit	Margin	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	174.979	22.40	-17.36	33.5	11.10	Peak	323.00	300	Horizontal	Pass
2	218.375	25.46	-14.90	36.0	10.54	Peak	329.00	300	Horizontal	Pass
3	318.503	22.19	-11.85	36.0	13.81	Peak	0.00	300	Horizontal	Pass
4	479.968	27.24	-8.21	36.0	8.76	Peak	204.00	200	Horizontal	Pass
5	649.918	27.31	-4.85	36.0	8.69	Peak	120.00	100	Horizontal	Pass
6	974.786	30.44	-0.48	44.0	13.56	Peak	227.00	100	Horizontal	Pass



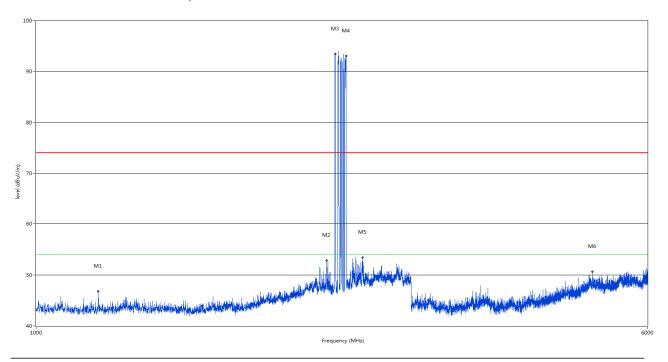
A.1.3 Test Antenna Vertical, 1 GHz – 6 GHz



No.	Frequency	Results	Factor (dB)	Limit	Margin	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	2037.000	49.28	0.14	74.0	24.72	Peak	206.00	100	Vertical	Pass
2	2345.000	53.11	1.25	74.0	20.89	Peak	322.00	100	Vertical	Pass
3	2402.000	93.94	1.23	74.0	-19.94	Peak	353.40	100	Vertical	N/A
4	2480.500	93.54	1.67	74.0	-19.54	Peak	349.10	100	Vertical	N/A
5	5137.500	51.25	11.05	74.0	22.75	Peak	5.00	100	Vertical	Pass
6	5786.250	51.64	11.51	74.0	22.36	Peak	0.00	100	Vertical	Pass



A.1.4 Test Antenna Horizontal, 1 GHz – 6 GHz



No.	Frequency	Results	Factor (dB)	Limit	Margin	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	1199.500	46.77	-3.95	74.0	27.23	Peak	107.00	100	Horizontal	Pass
2	2343.000	52.79	1.17	74.0	21.21	Peak	4.00	100	Horizontal	Pass
3	2404.000	93.44	1.25	74.0	-19.44	Peak	170.00	100	Horizontal	N/A
4	2479.500	93.06	1.62	74.0	-19.06	Peak	90.00	100	Horizontal	N/A
5	2604.500	53.40	3.70	74.0	20.60	Peak	237.00	100	Horizontal	Pass
6	5105.250	50.61	11.19	74.0	23.39	Peak	3.00	100	Horizontal	Pass

A.2 Conducted Emission

Note: Not applicable.



ANNEX B TEST SETUP PHOTOS

Please refer the document "BL-SZ1750414-AE.PDF".

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document "BL-SZ1750414-AW 1.PDF".

ANNEX D EUT INTERNAL PHOTOS

Please refer the document "BL-SZ1750414-AI 1.PDF".

--END OF REPORT--